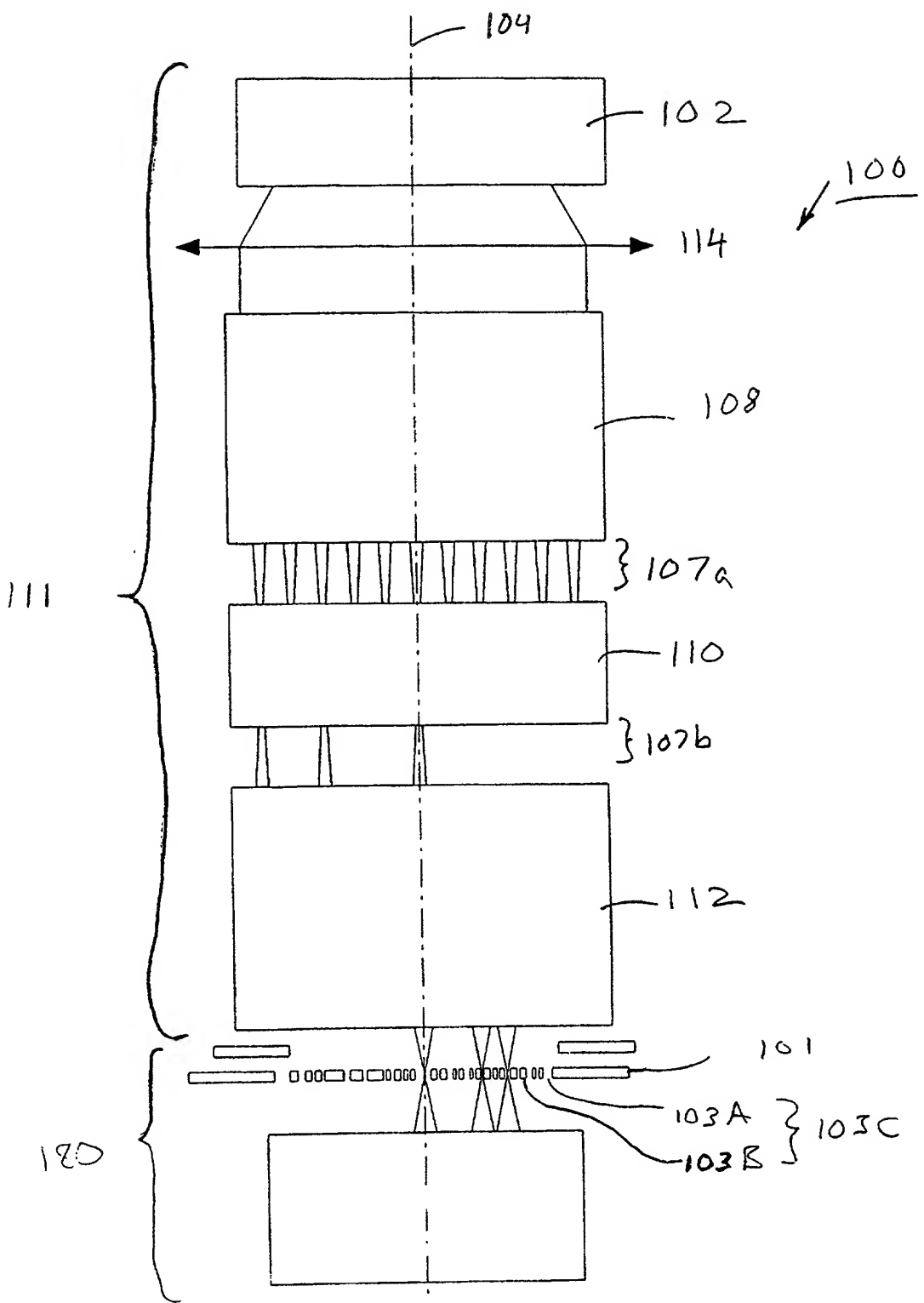
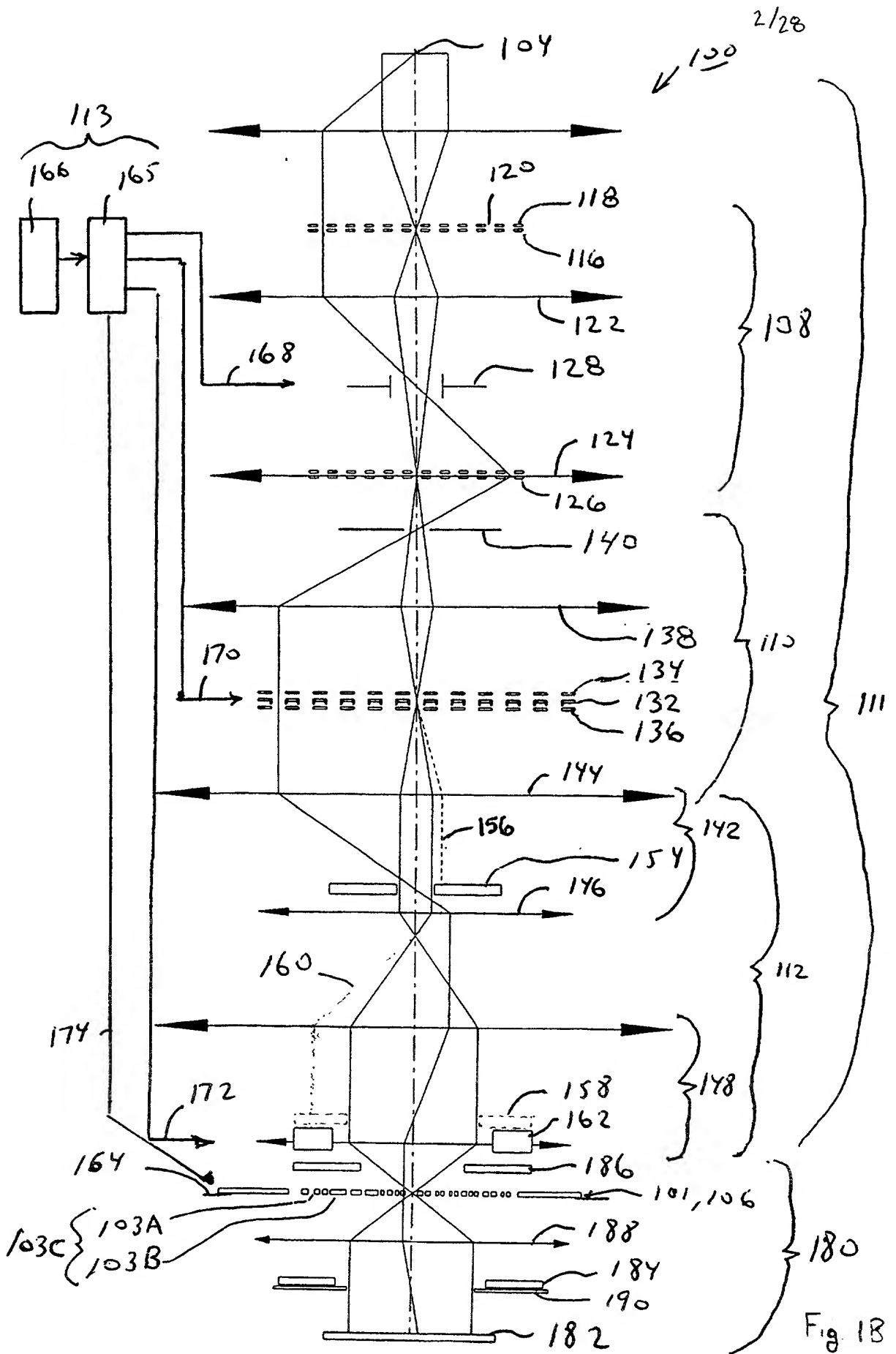
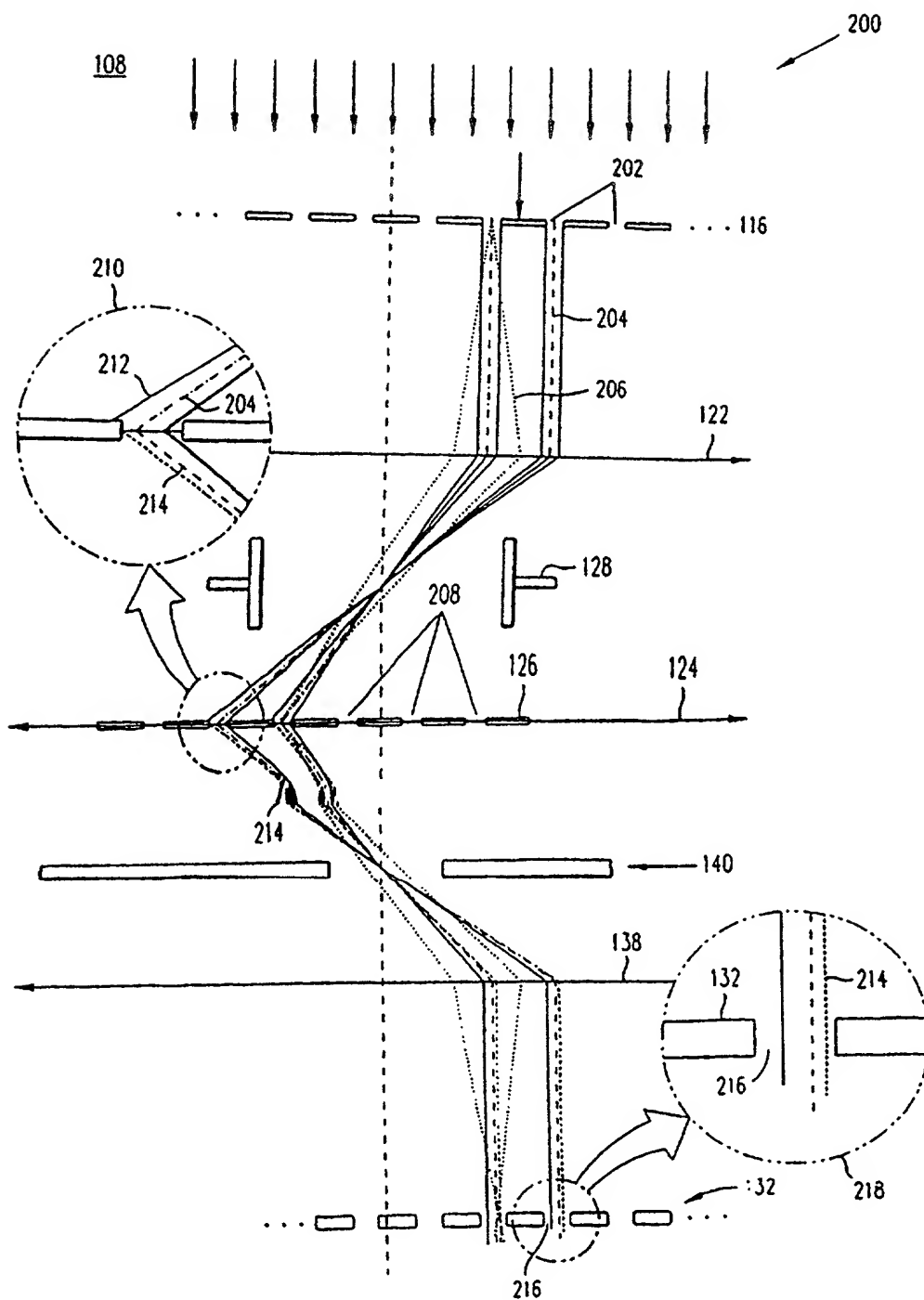


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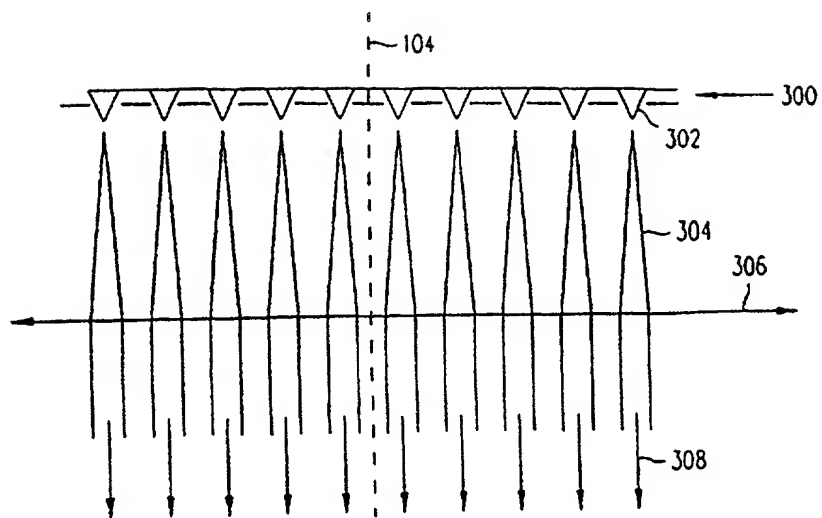


FIG. 3A

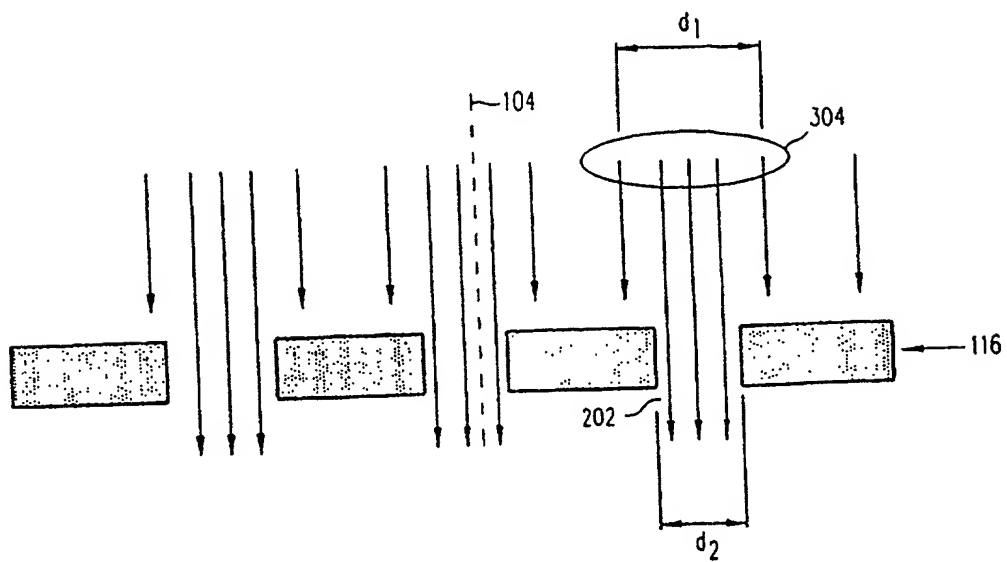


FIG. 4

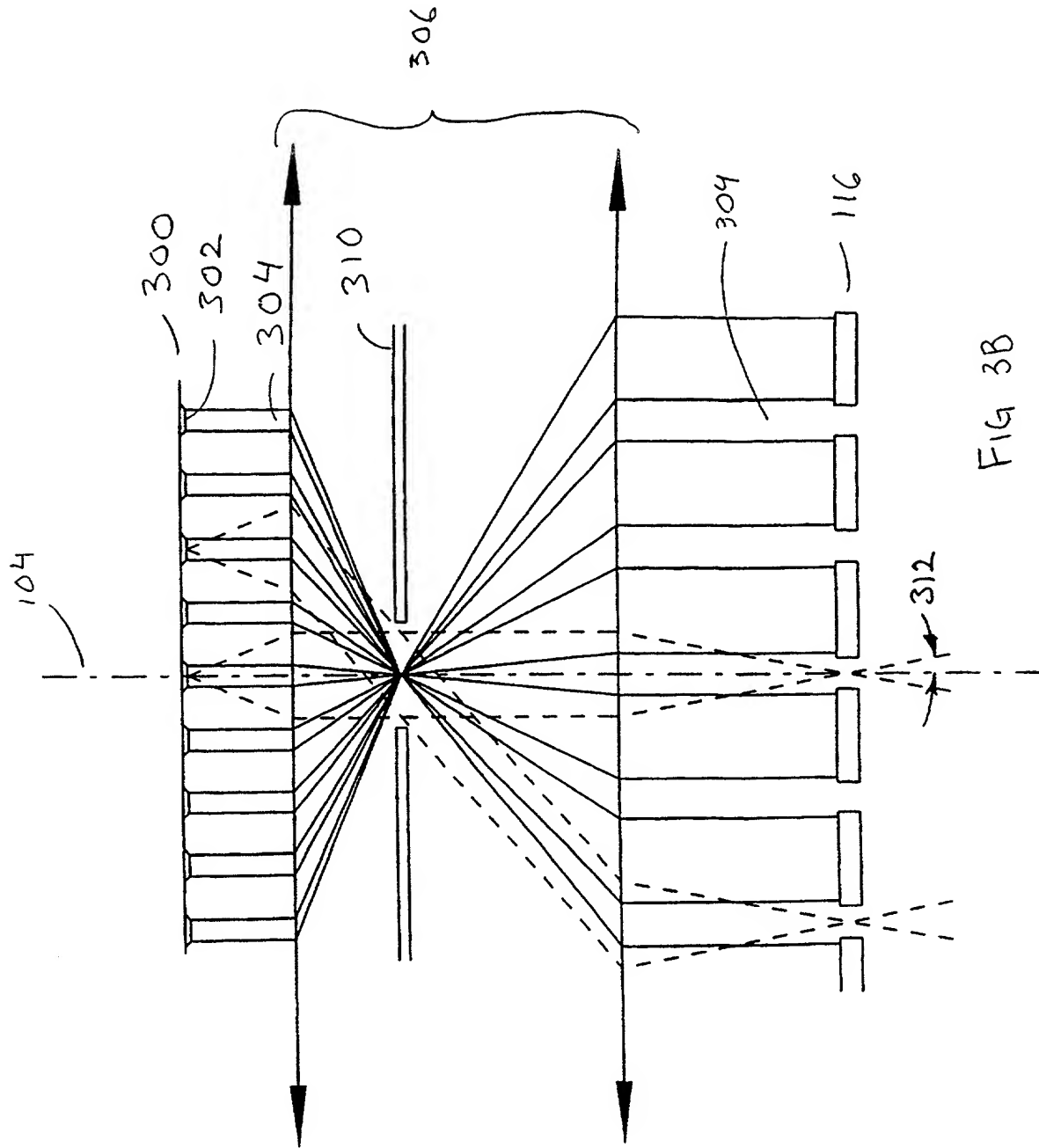


FIG. 3B

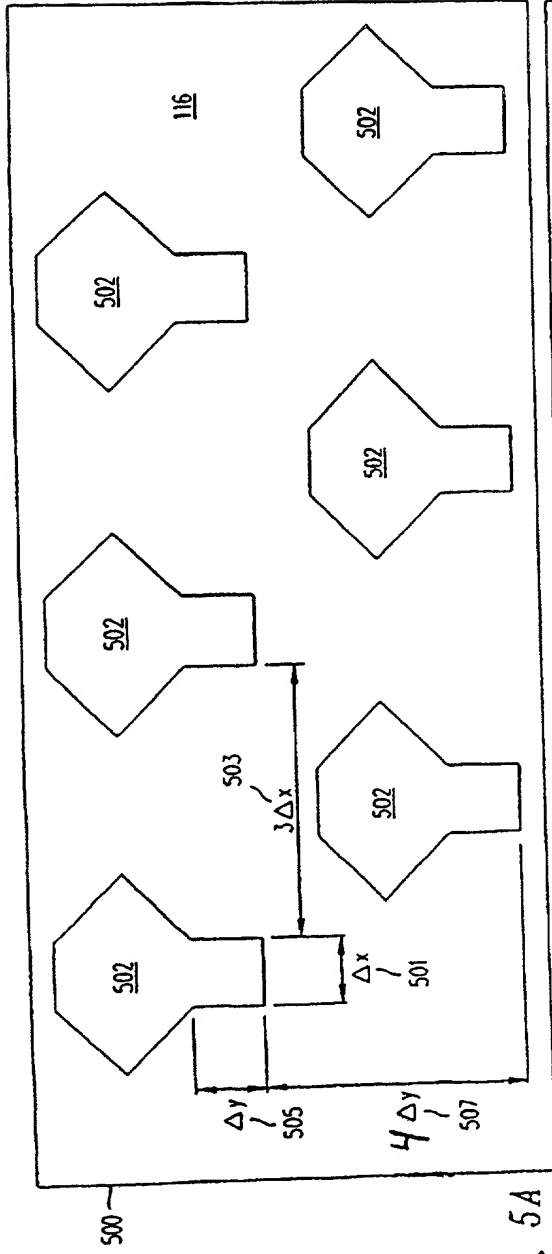


FIG. 5A

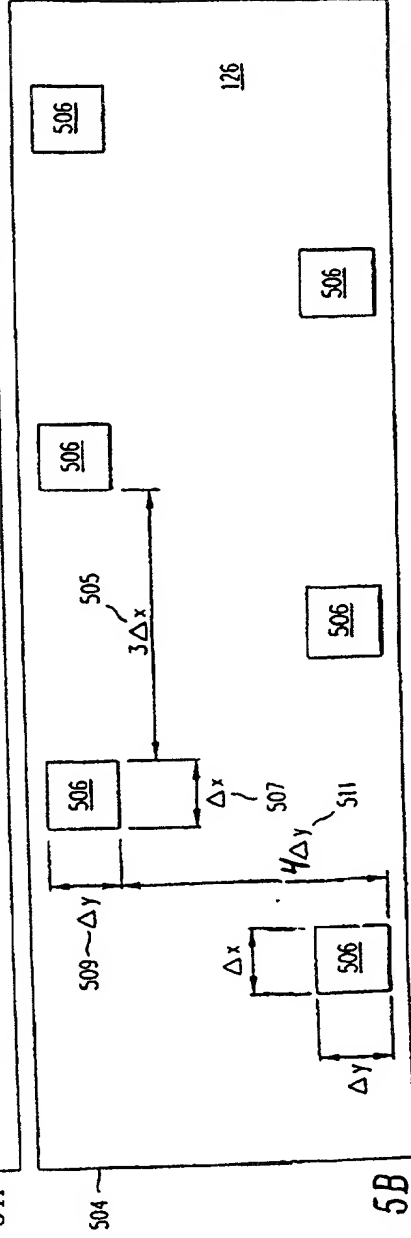
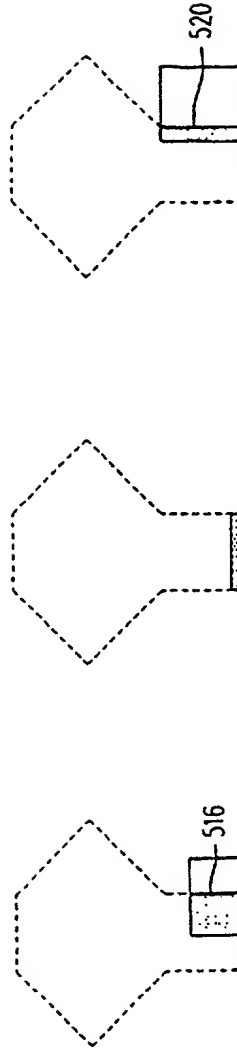
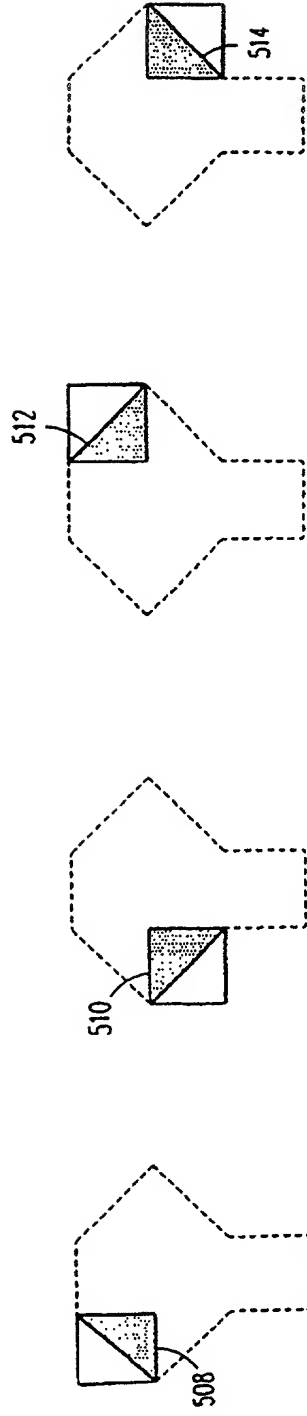


FIG. 5B

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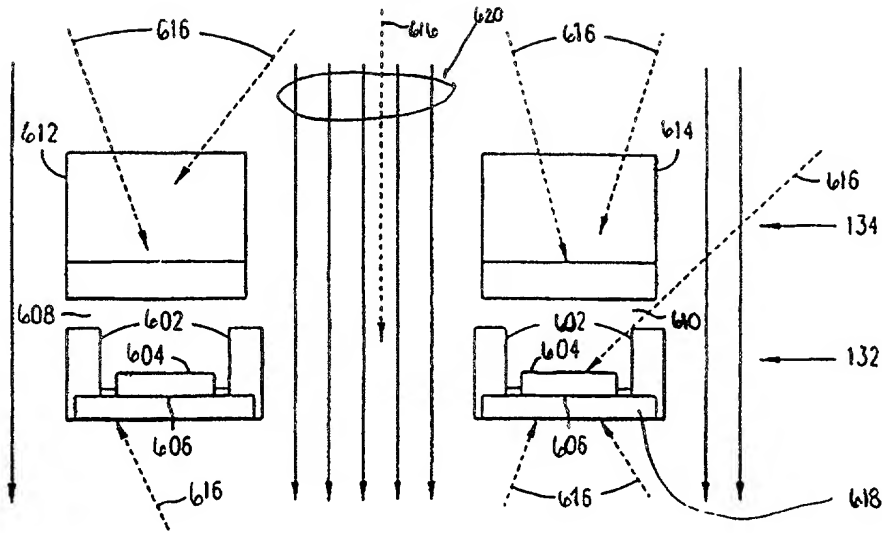


FIG. 6

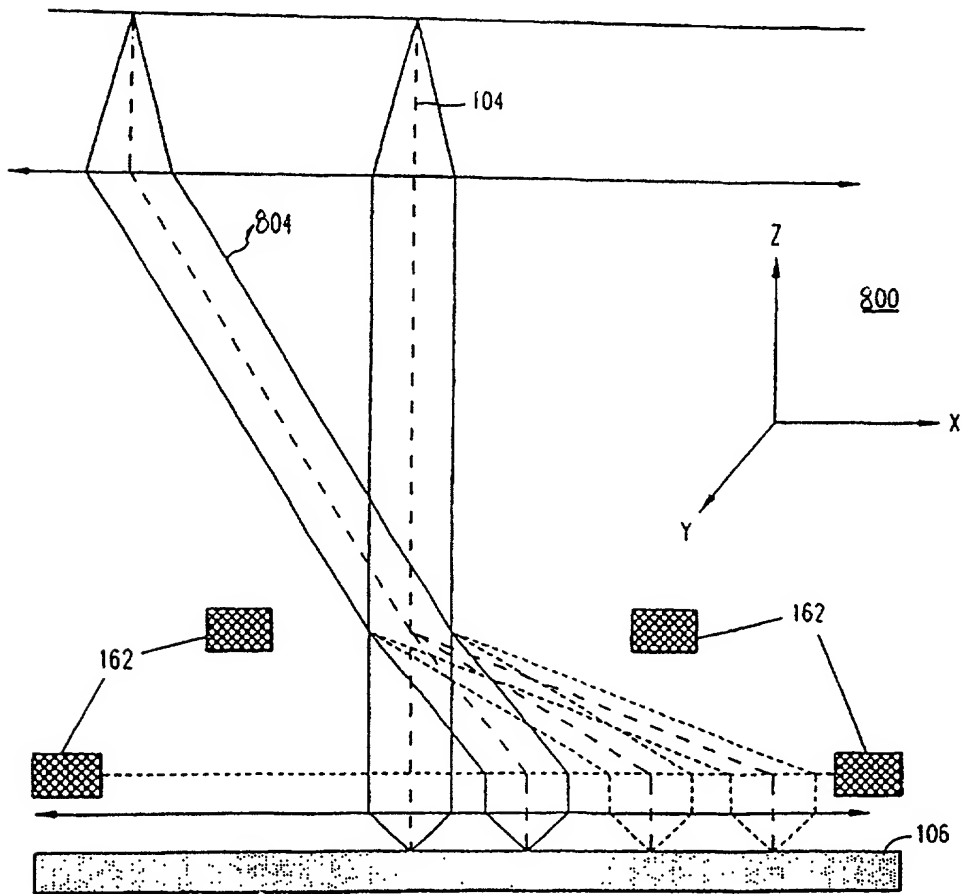


FIG. 8

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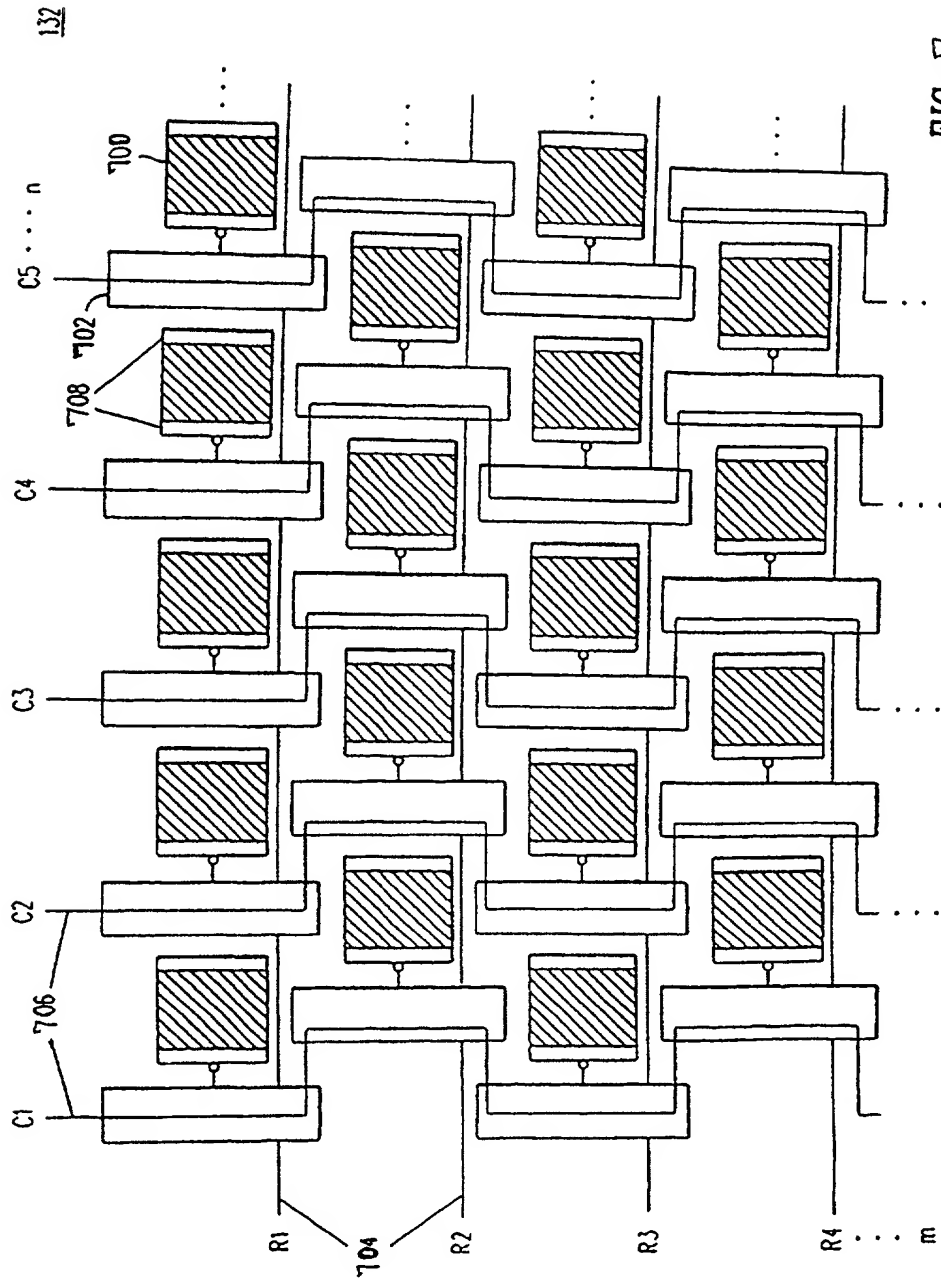


FIG. 7

904

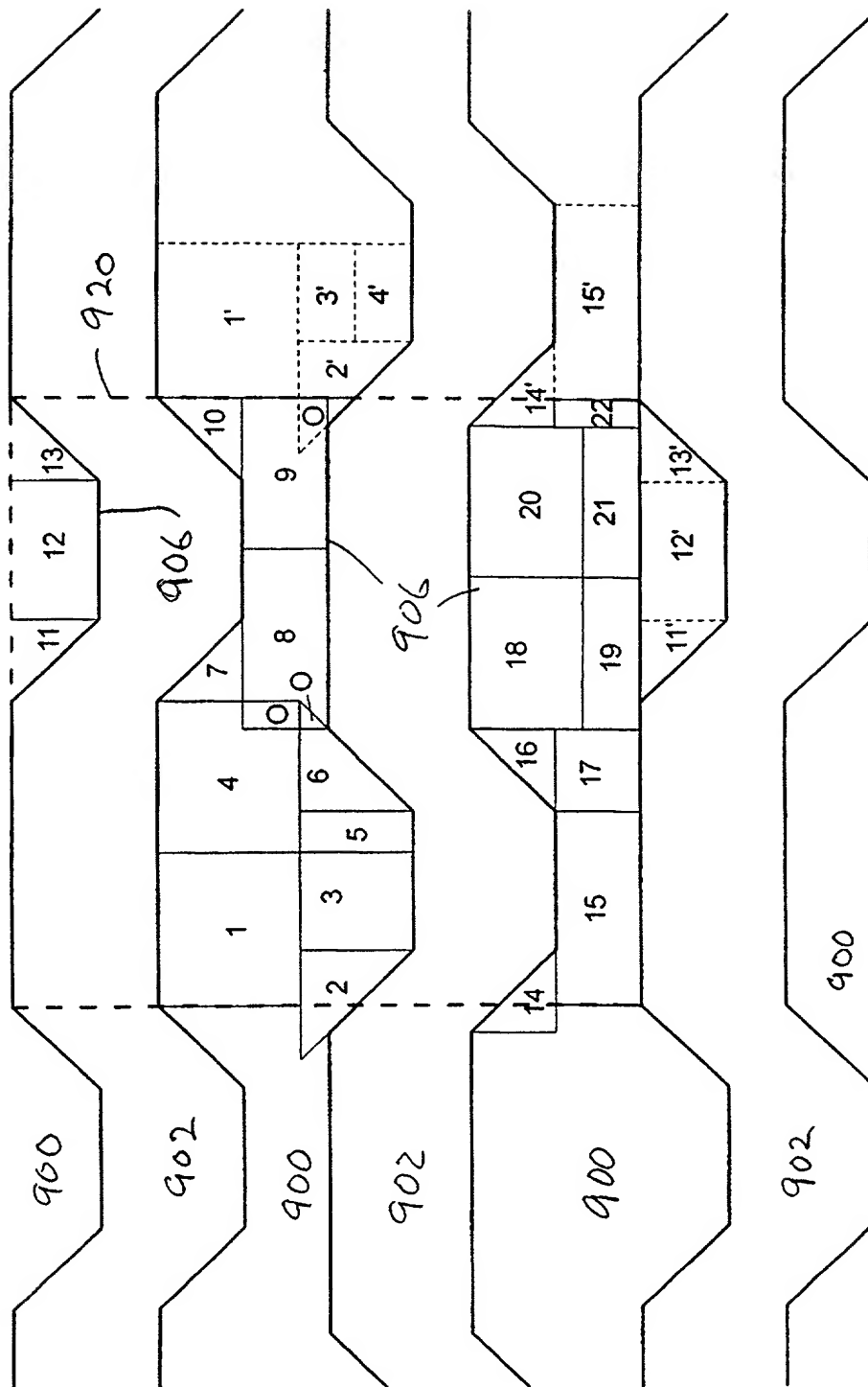


Figure 9A

904

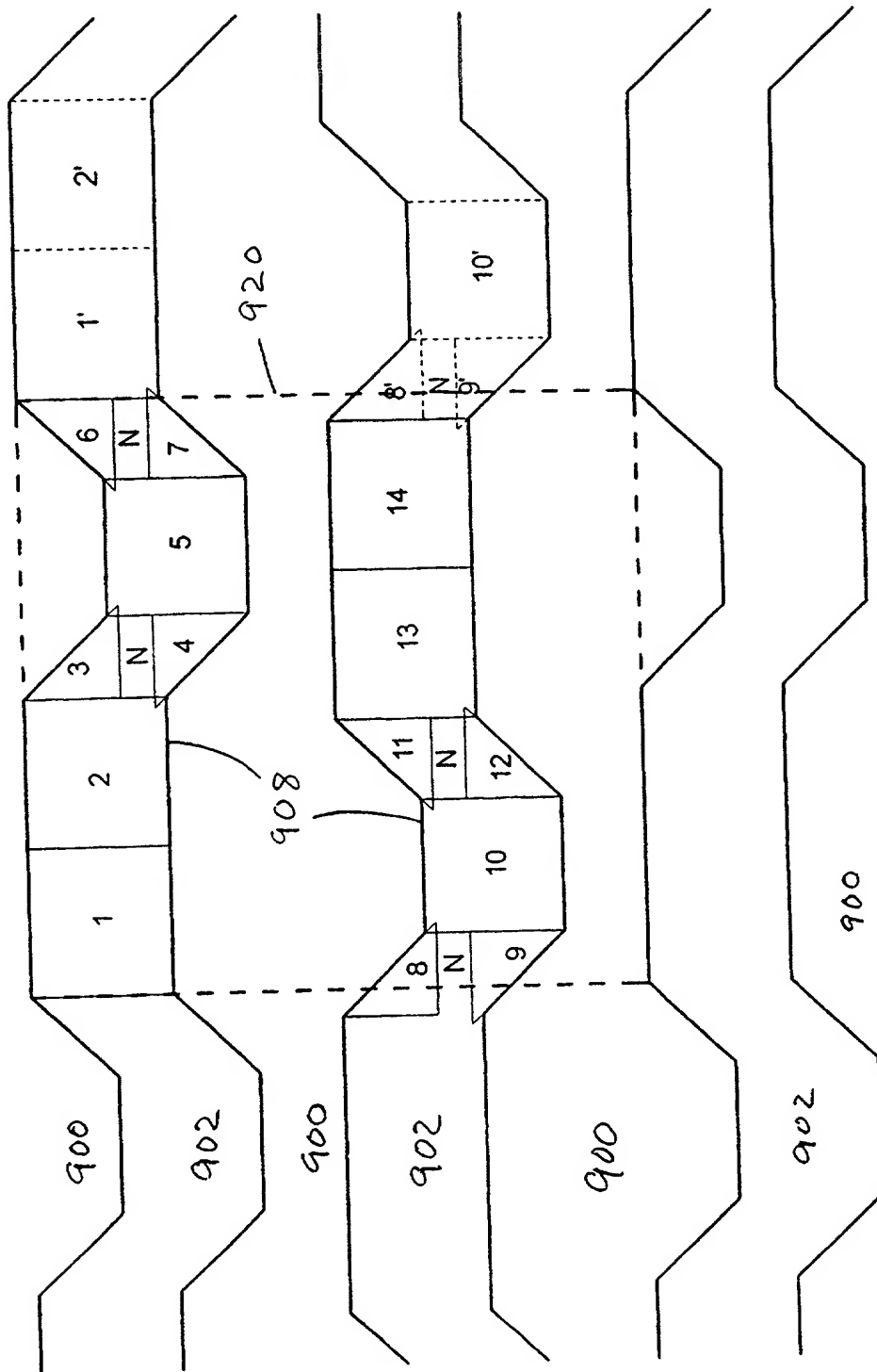


Figure 9B

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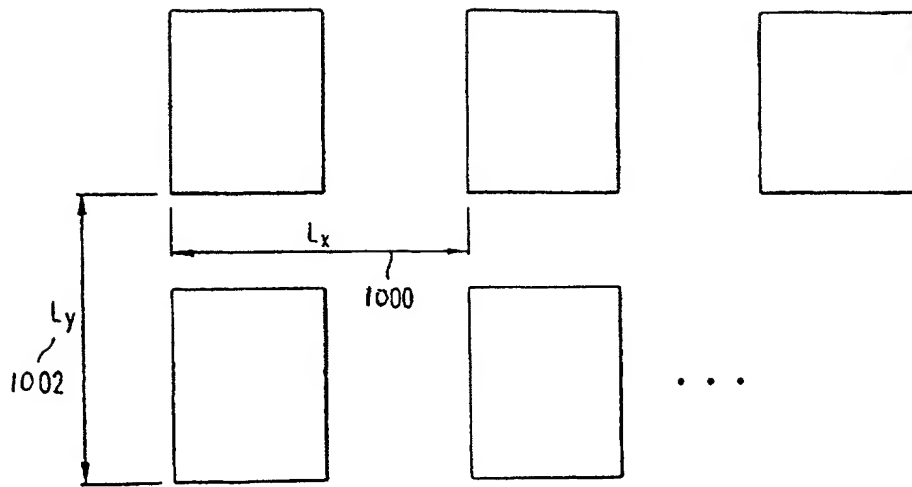


FIG. 10A

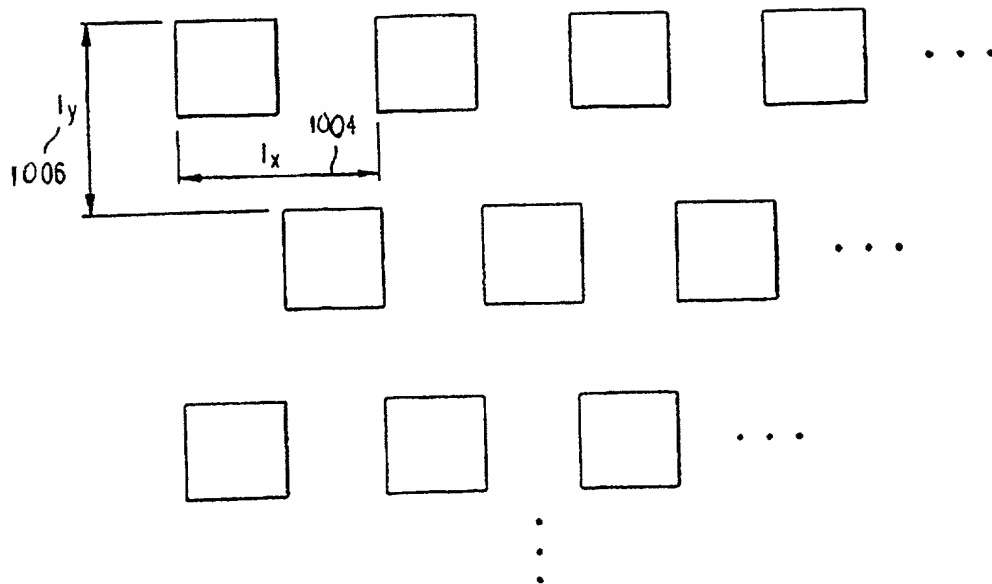
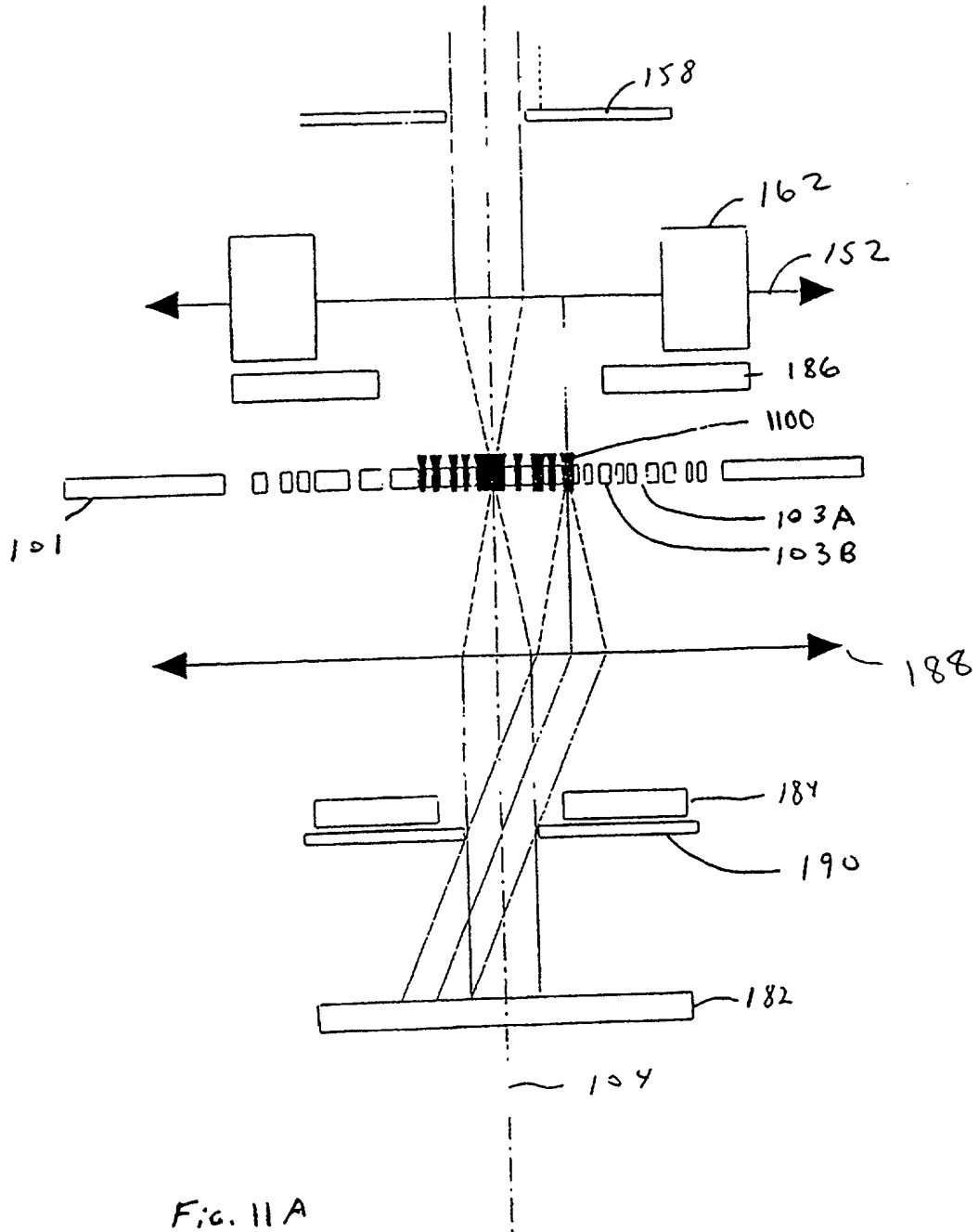


FIG. 10B

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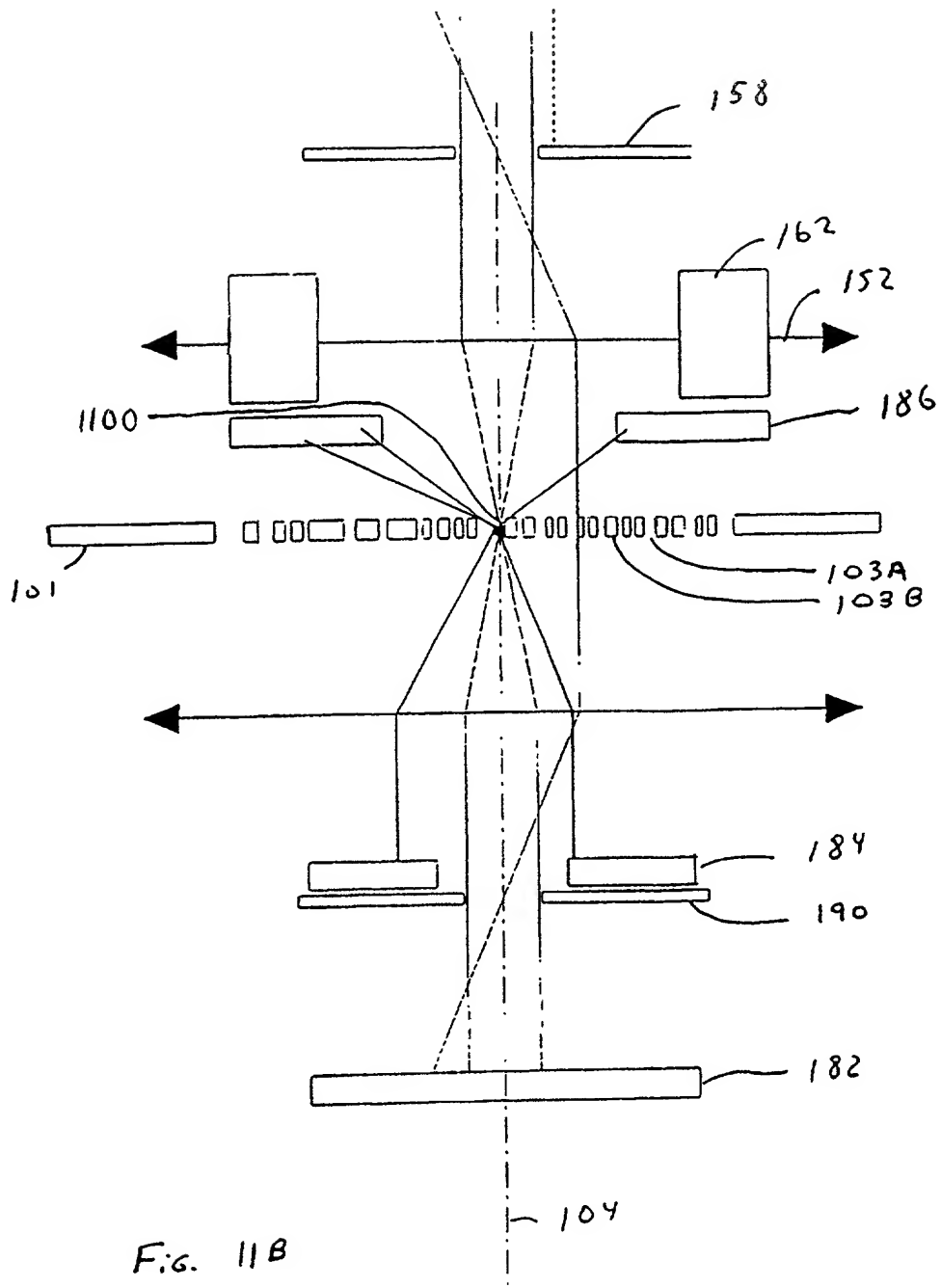
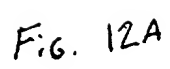


Fig. 11B

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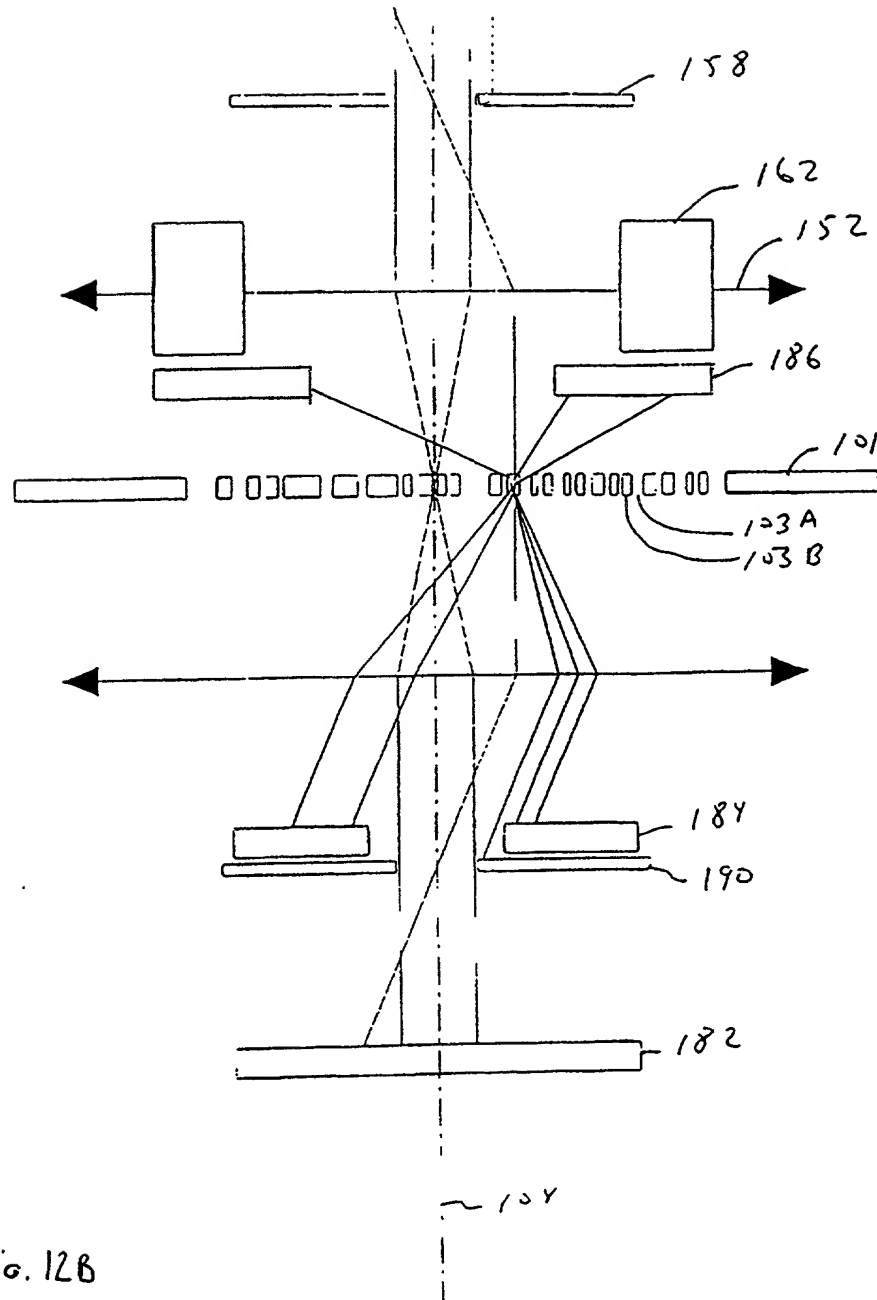


Fig. 12B

Stencil Mask Defect Detection

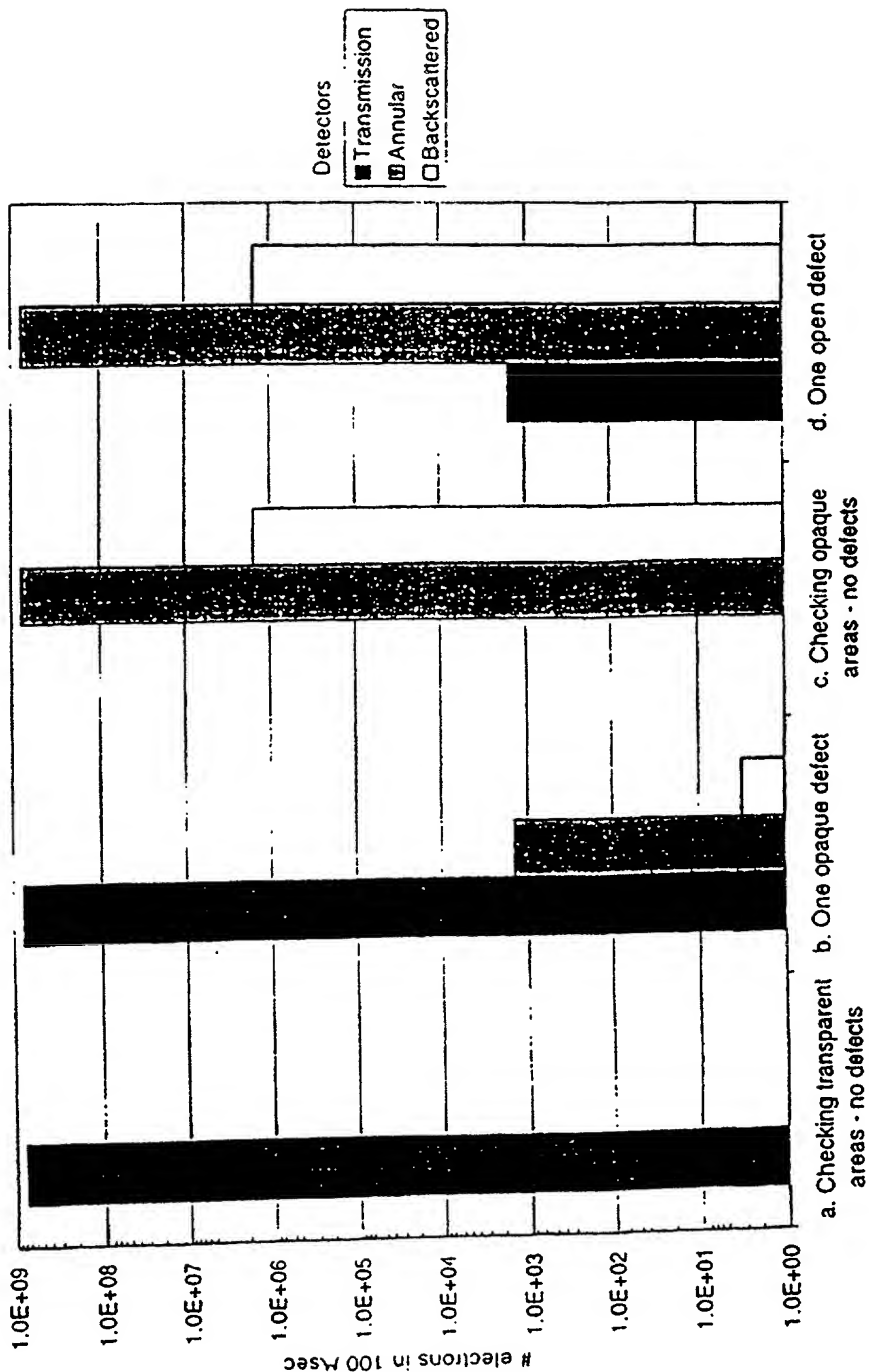
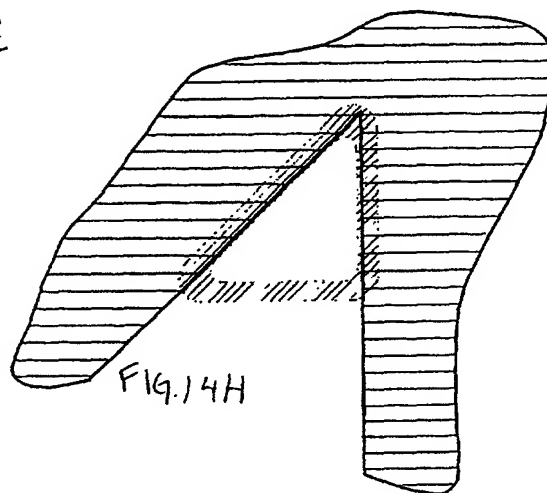
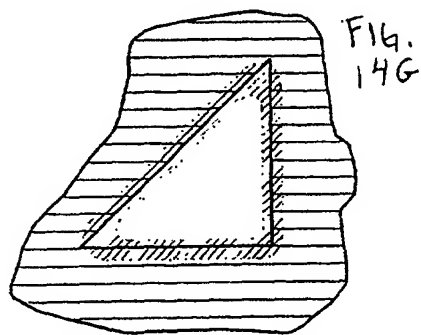
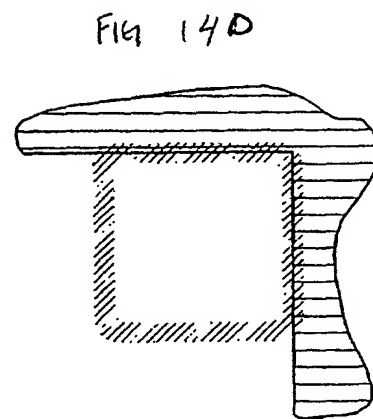
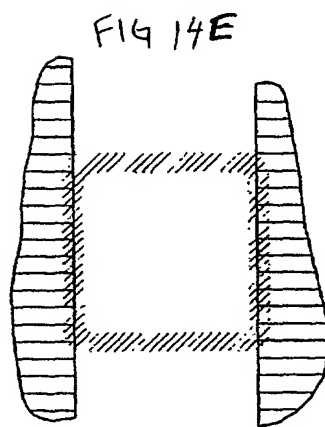
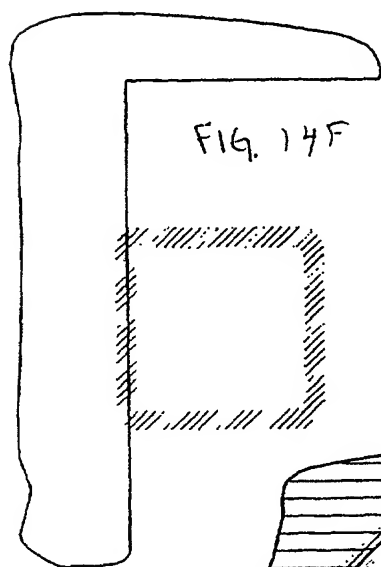
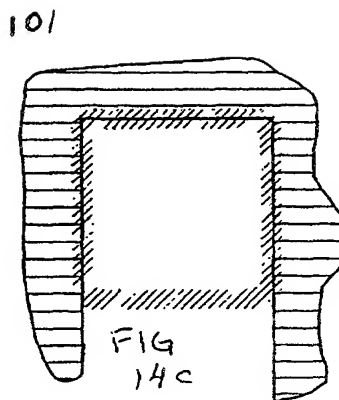
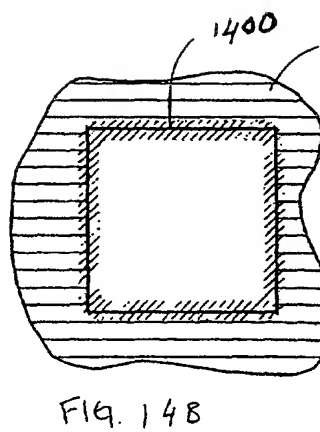
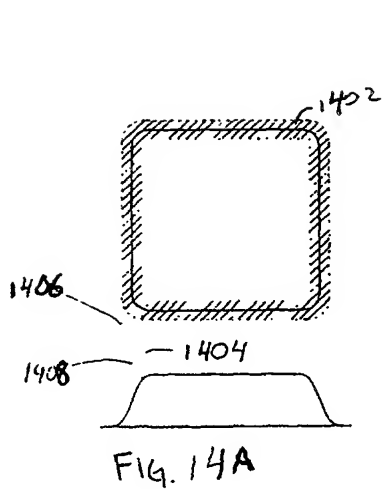


Fig. 13

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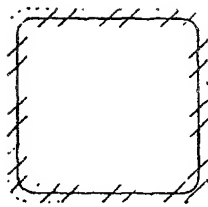


FIG.
14 I

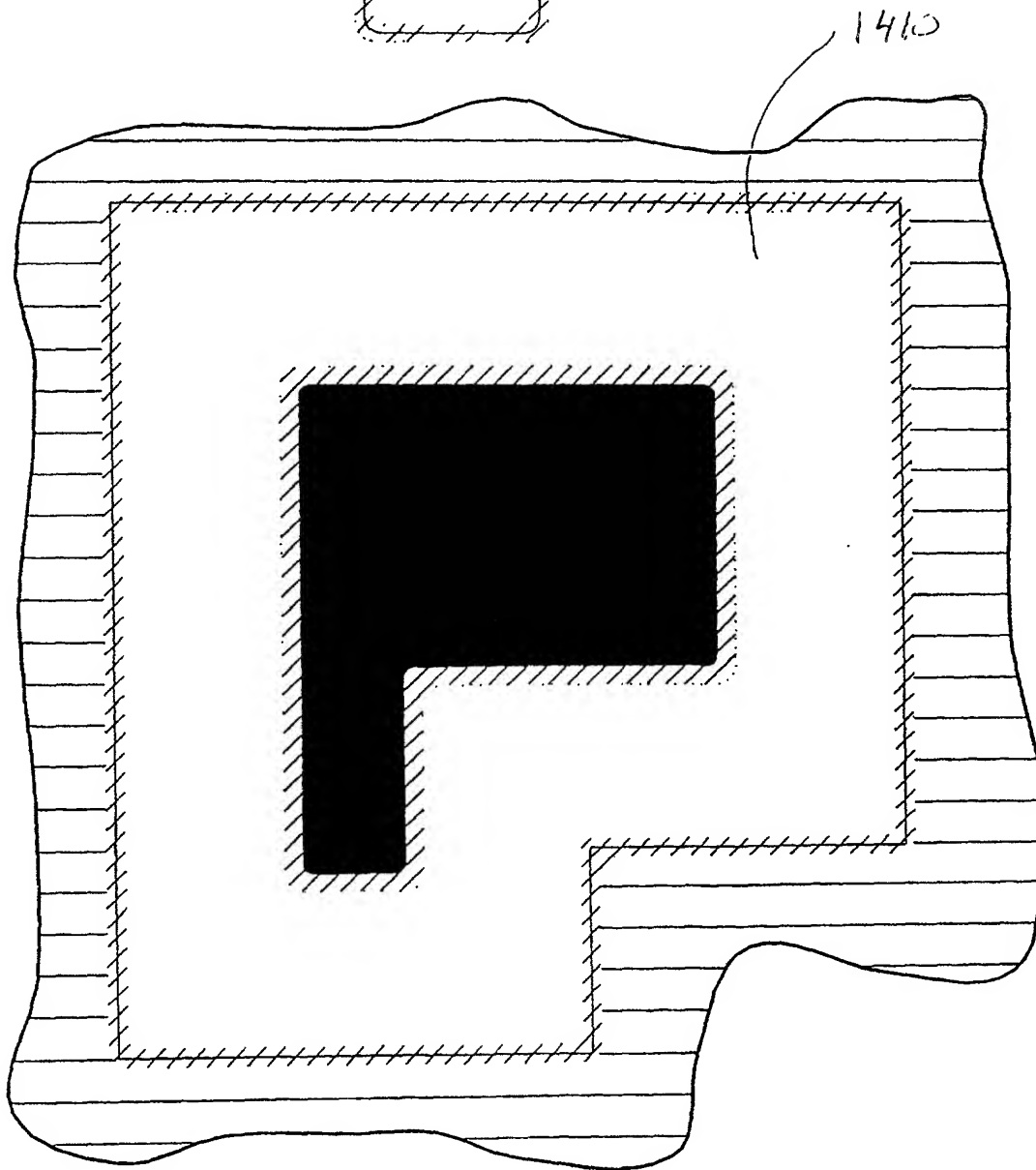
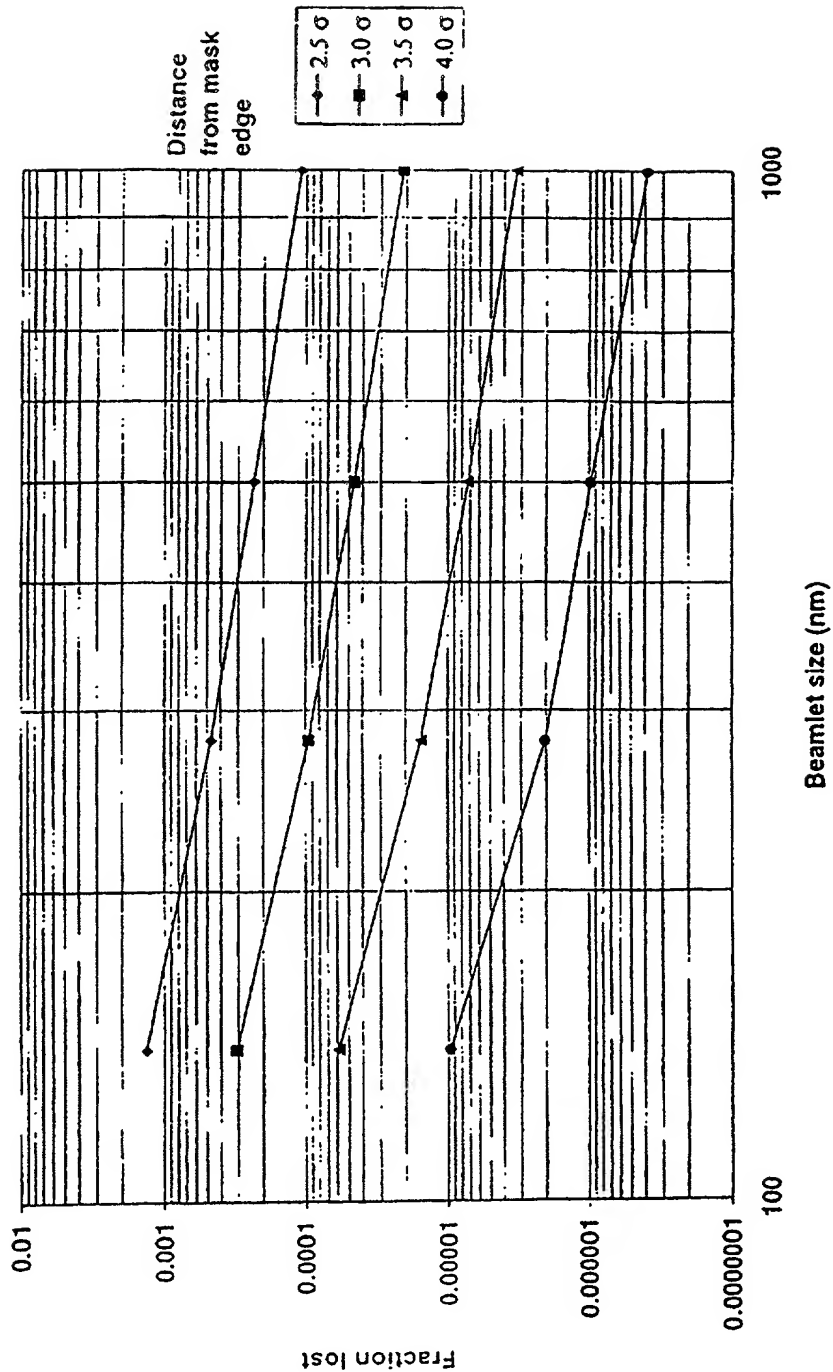


FIG. 14 J

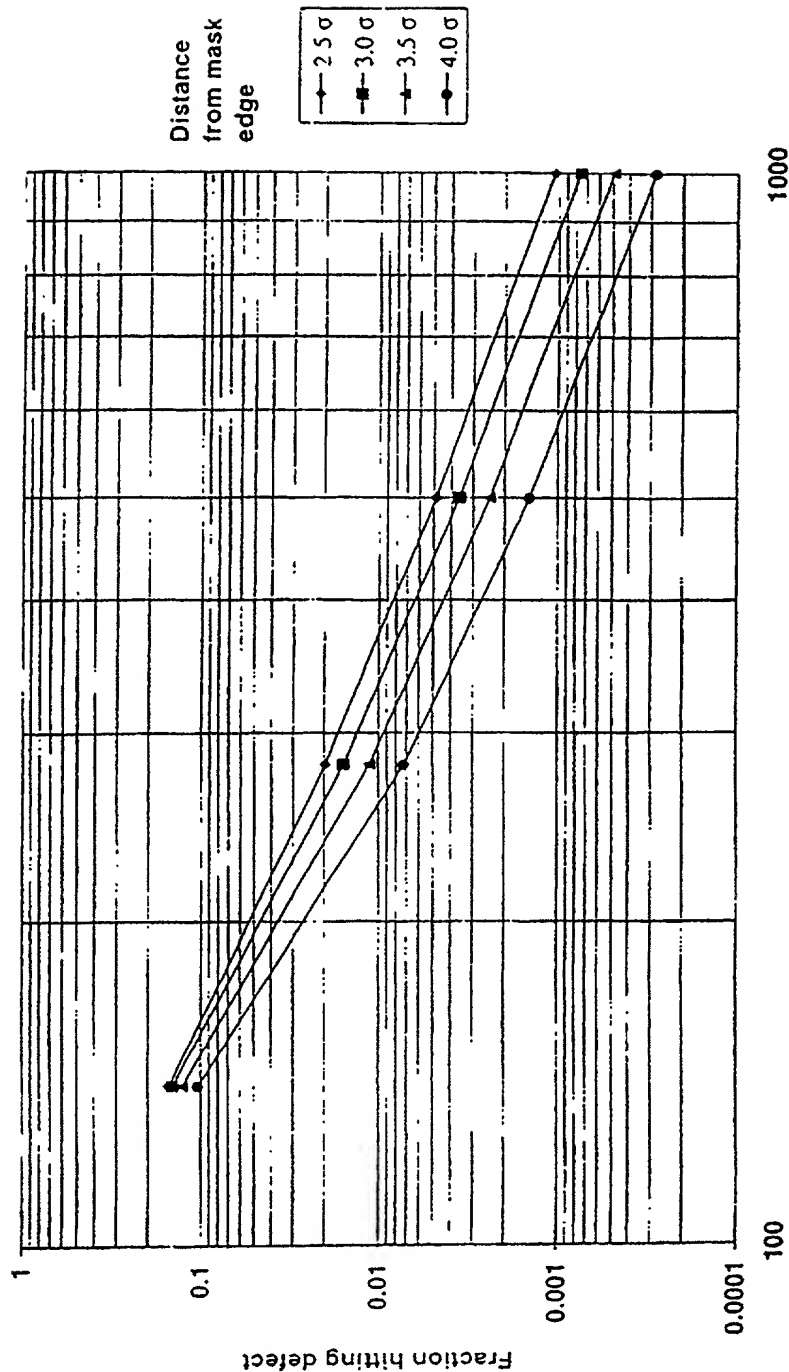
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Fraction of beamlet lost on mask (on all four sides)
edgewidth (12/88) = 30 nm; $1 \sigma = 12.77 \text{ nm}$



F.C. 15A

Fraction of beamlet hitting 50 nm defect
edgewidth (12/88) = 30 nm; 1 s = 12.77 nm



Beamlet size (nm)

FIG. 158

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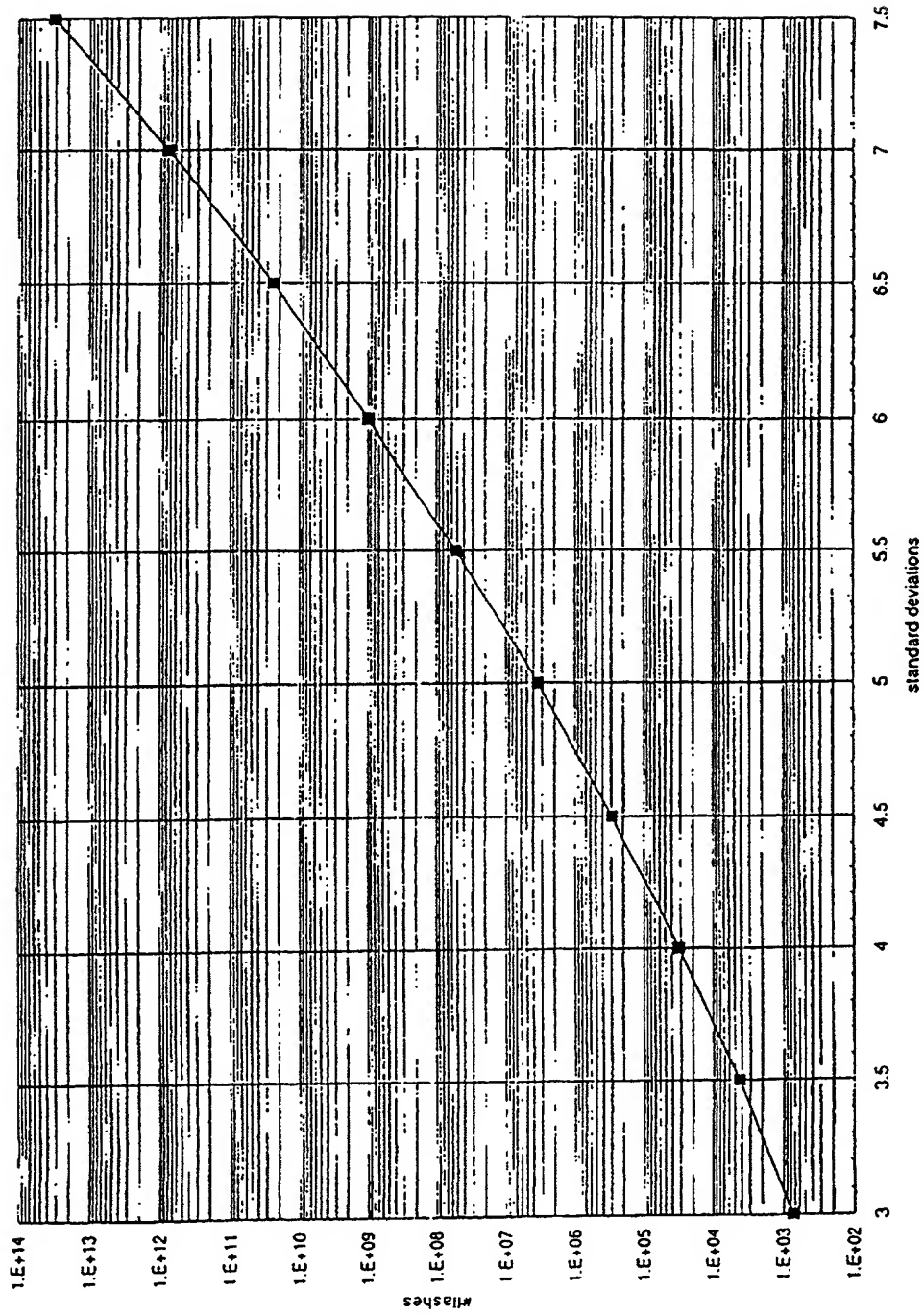


Fig. 15C

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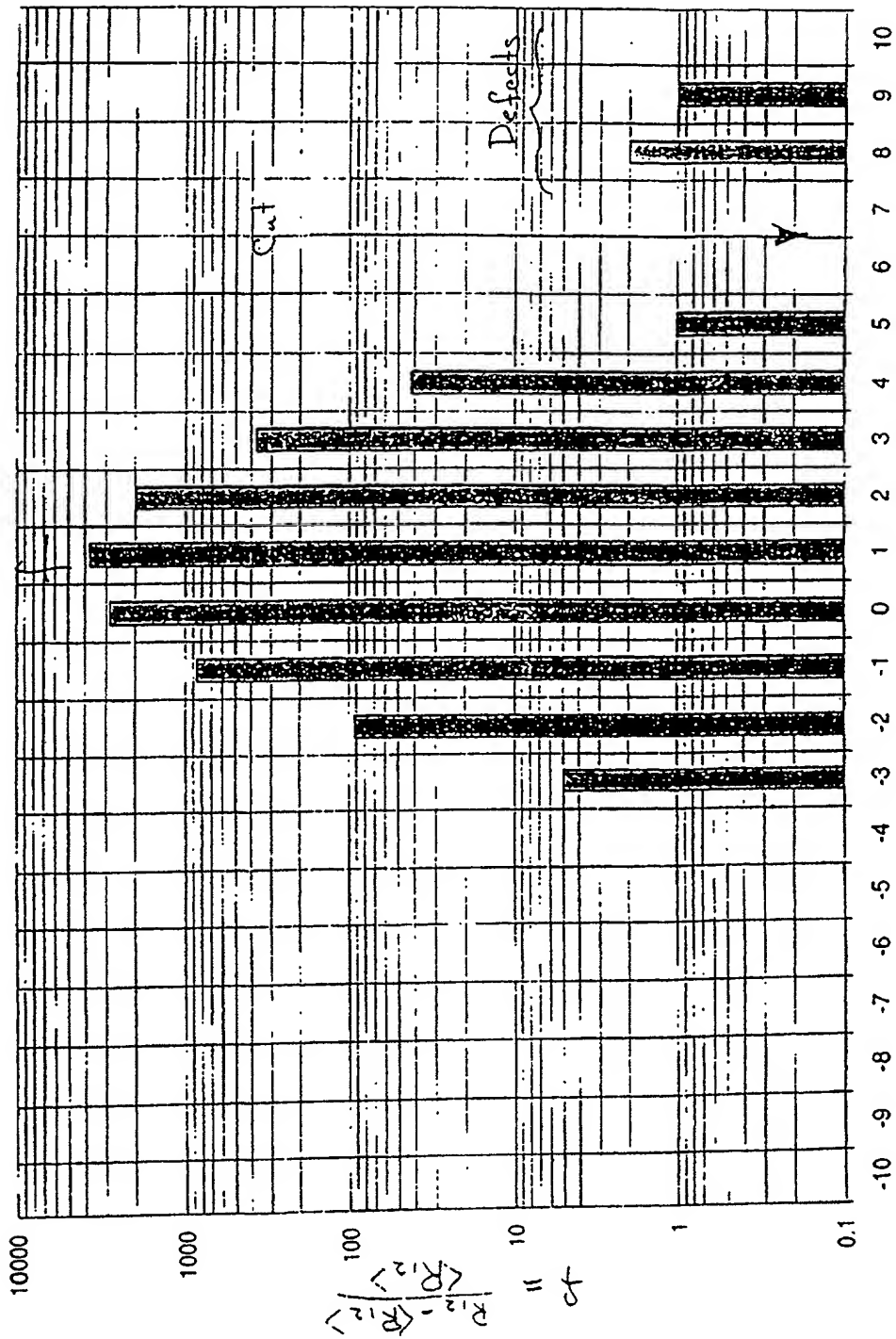


Fig 150

f/df for clear and opaque defects

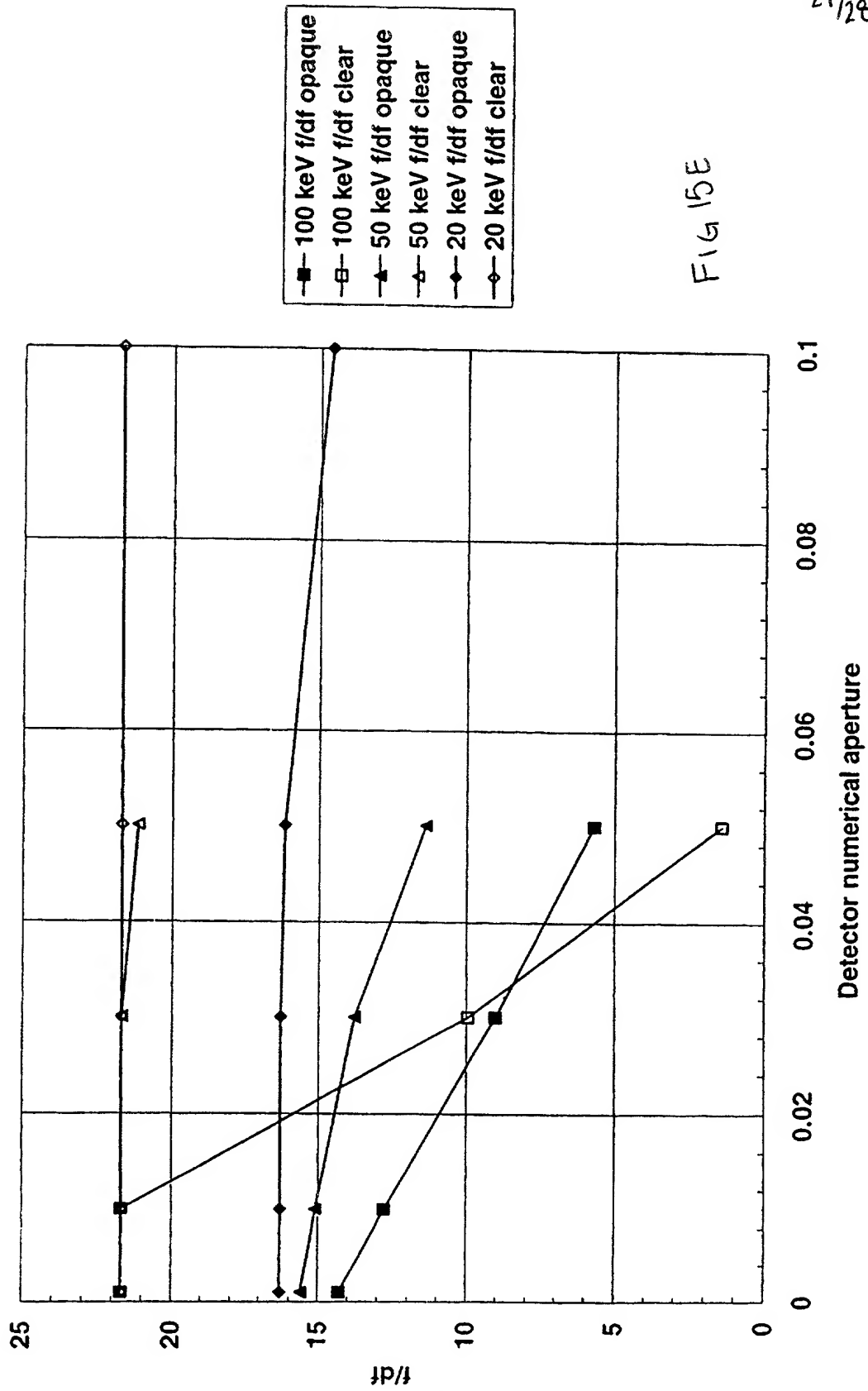


FIG 15E

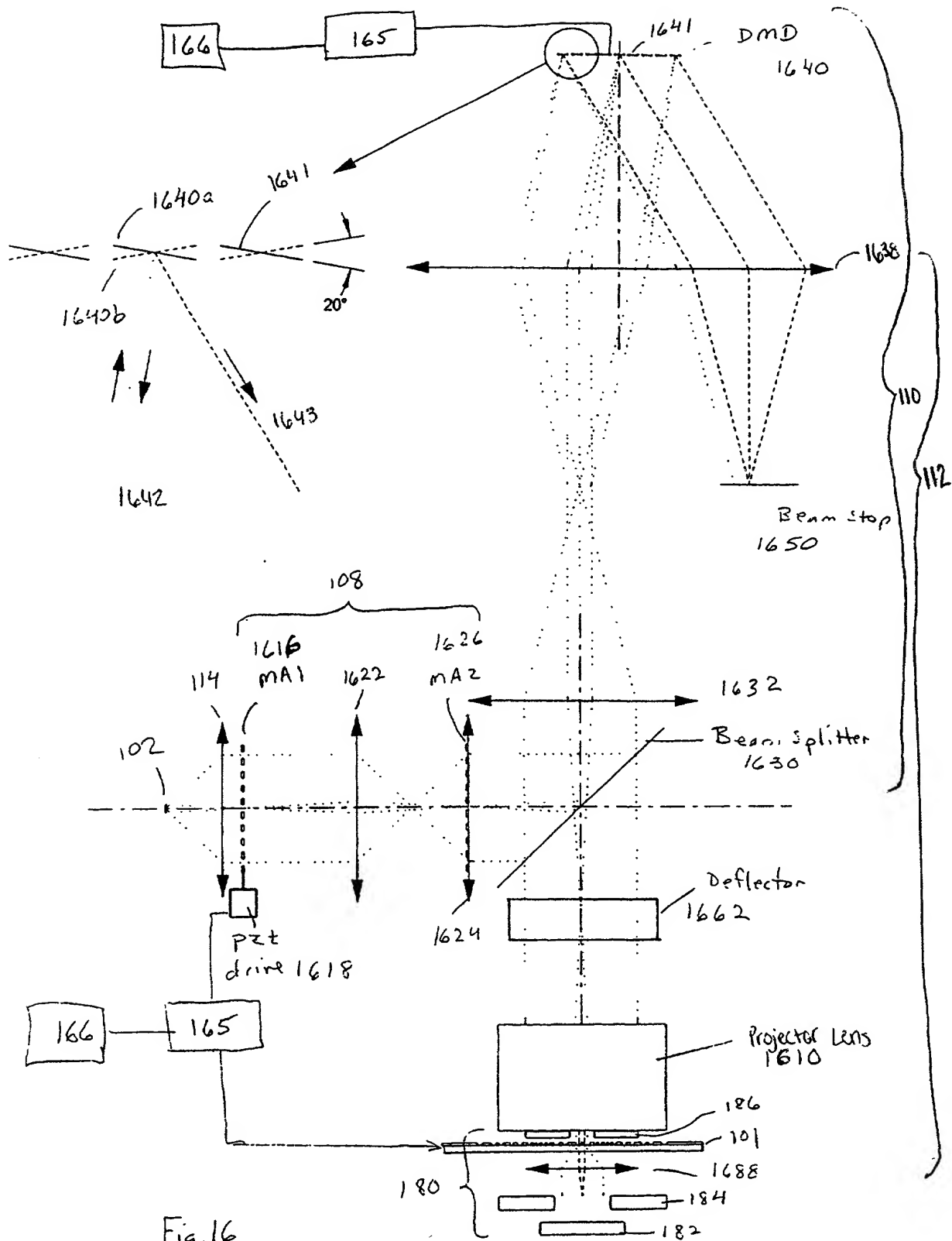


Fig. 16

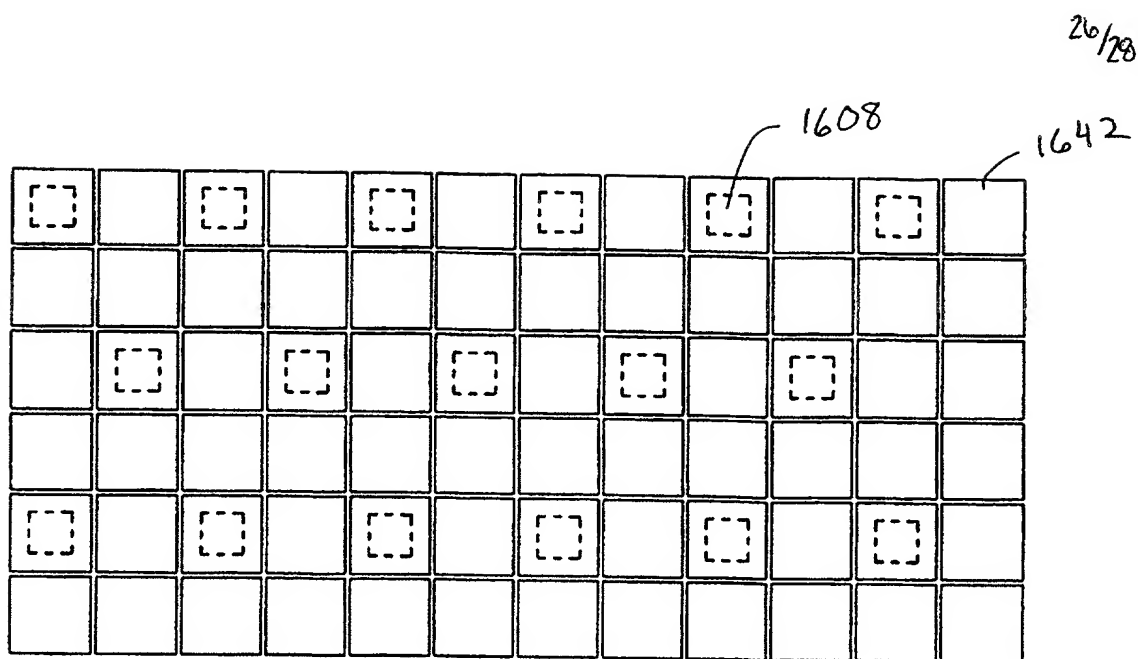


Fig. 17a

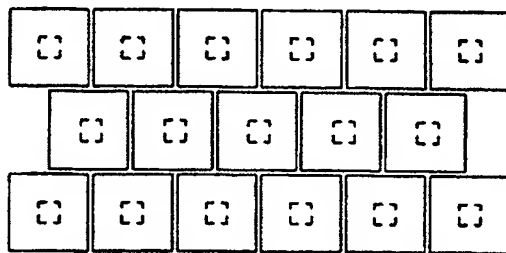


Fig. 17b

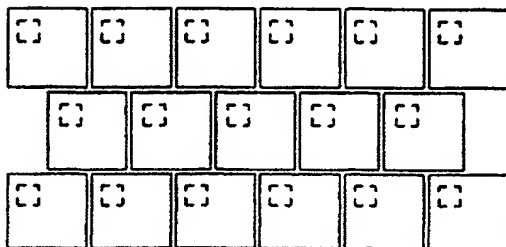


Fig. 17c

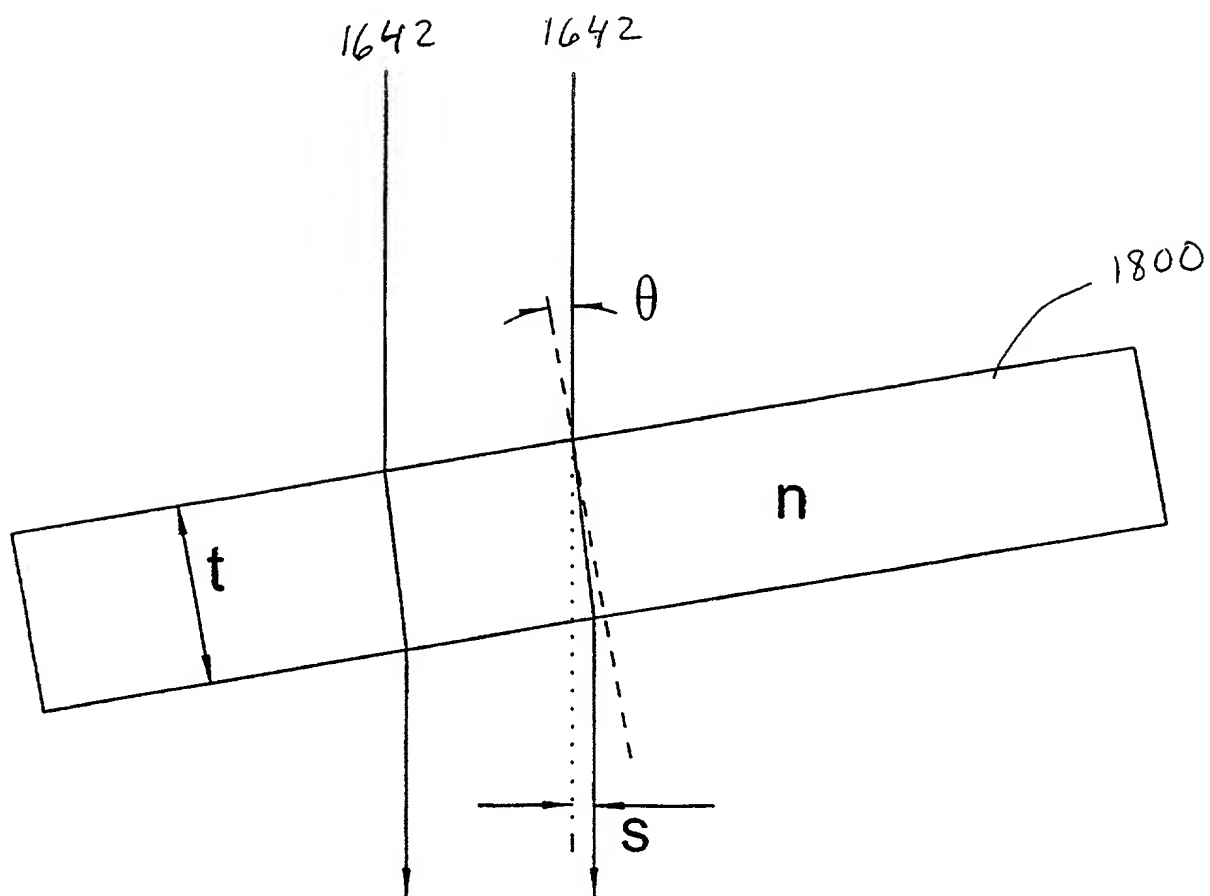


Fig 18

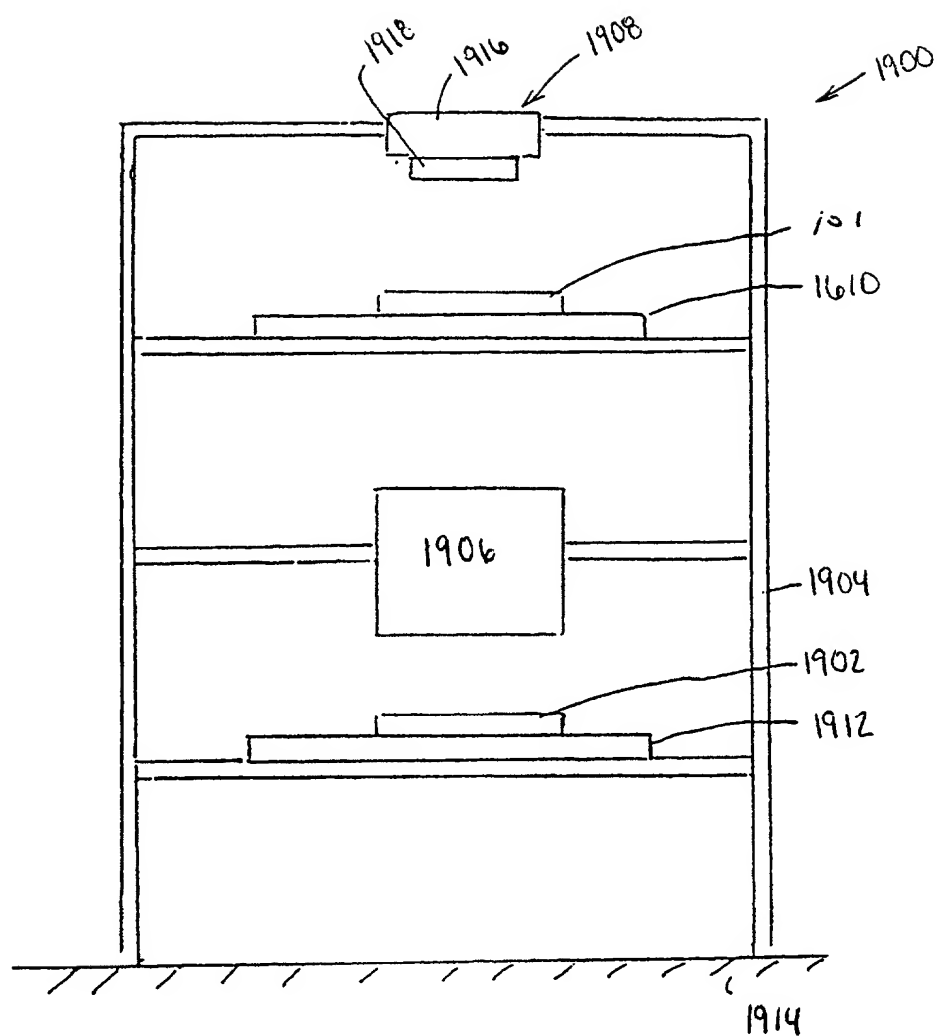


Fig 19